Search Notes				

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/004,885	ABURAKAWA ET AL.	
Examiner	Art Unit	
Khai M Nguyen	2687	

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	SEARCHED				
Class	Subclass	Date	Examiner		
455	561 550.1 560 73	9/9/2005	KN		
379	56.2 56.1	9/9/2005	KN		
379	429	9/9/2005	KN		
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INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner
see	attached		KN
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SEARCH (INCLUDING SEA	I NOTES RCH STRATEG	Υ)
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